

James Colvin receives the 2026 EDFAS Lifetime Achievement Award



The **EDFAS Lifetime Achievement Award**

recognizes those who have given their time, knowledge, and abilities toward the advancement of the electronic device failure analysis industry.

The 2026 awardee is **Mr. James Colvin**, (Jim) comes from the Midwest and holds an electrical engineering degree from Purdue University. He has 36 years of contributions to the failure analysis community through committee organizations for

ISTFA, EOS/ESD, IPFA and IRPS and has published more than 20 papers on failure analysis techniques. Colvin is a past AV Chair, Expo Chair and Tutorial Chair for ISTFA and has been active each year since 1990.

Colvin has worked as a consultant for over 31 years and originated the Passive Voltage Contrast (PVC) technique and pushed a reluctant industry to accept the validity of the Atomic Force Microscope/SPM for imaging and capacitive implant profiling. The joy and passion of inventing led to the first portable Emission Microscope, the Vibration coupler, and the laser illuminator, to name a few. The PVC technique is still used through the industry today. Currently he is the CEO of FA Instruments Inc. a company founded to provide Photon

Emission/Thermal Laser Stimulus and consultation for failure analysis/sample prep. Current endeavors focus on development of automation software and hardware with techniques for system in package sample preparation. Colvin currently holds 15 patents for products relating to the semiconductor field and is recognized as a contributor to the advancement of semiconductor technologies.

He currently serves on the EDFAS Board of Directors, chair of the ISTFA Sample Prep Users Group and a contributing member of the education committee. In addition, Colvin is a frequent presenter at ISTFA and has published nearly twenty articles, including articles and guest editorials in EDFA magazine. His two most recent publications are in the 7th Edition Microelectronics Desk Reference for “Frontside Sample Preparation” and “Backside Preparation and Optics” In addition he is a reviewer for publications in Journal of Materials Science: Materials in Electronics (JSME).